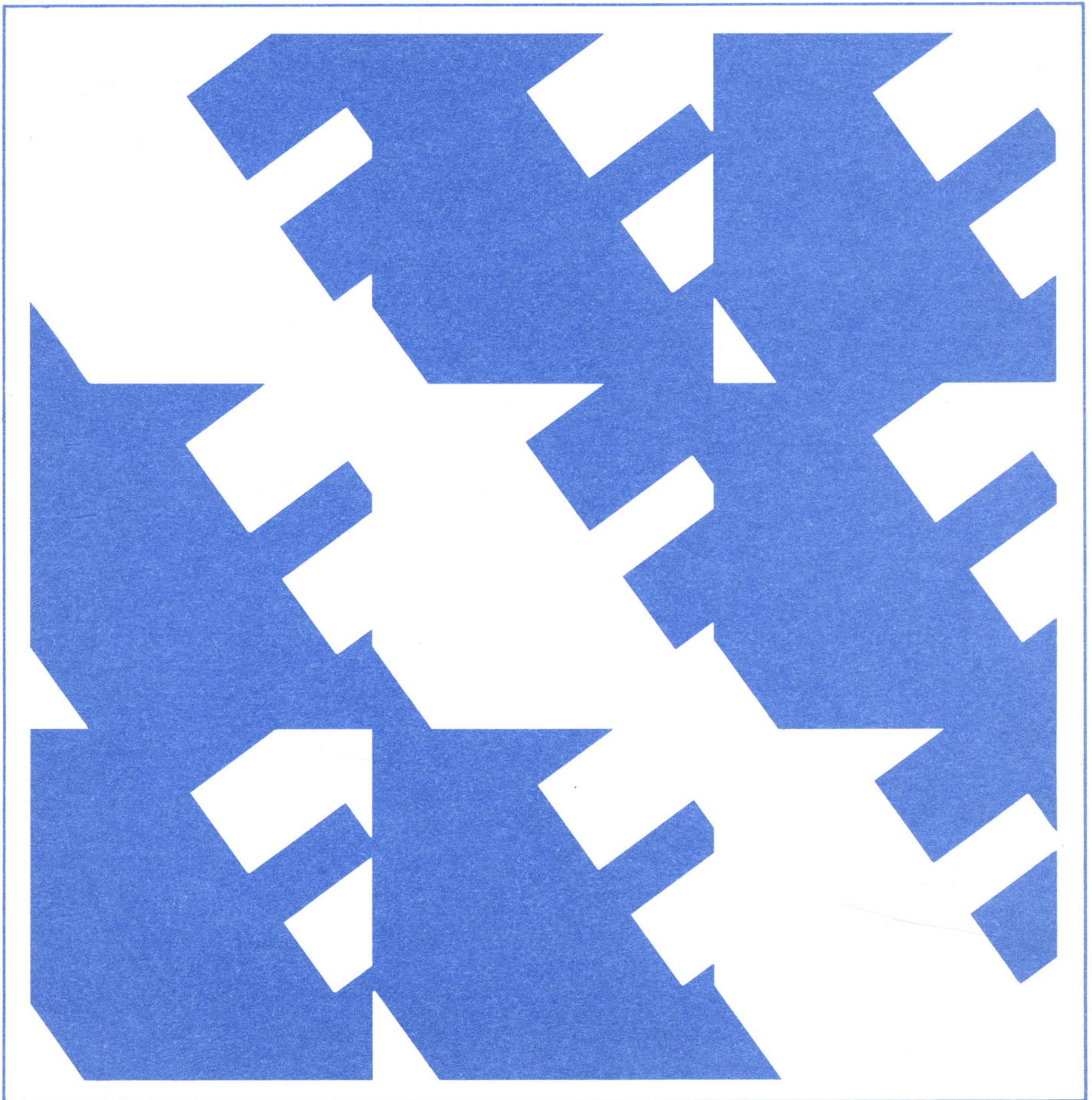


IEEE Standard for Semiconductor Memory Test Pattern Language

IEEE Std 660-1986



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Foreword

(This Foreword is not a part of IEEE Std 660-1986, IEEE Standard for Semiconductor Memory Test Pattern Language.)

This standard was developed to provide a common language for describing functional test sequences for memory devices. Members of the authoring committee include people from companies that produce automatic test equipment for testing semiconductor memories. The standard was first presented for discussion in draft form at the IEEE Test Technology Conference, November, 1980.

Suggestions for the improvement of this standard are welcome. They should be addressed to
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At the time this standard was approved, the Computer Memory Standards Working Group had the following membership:

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